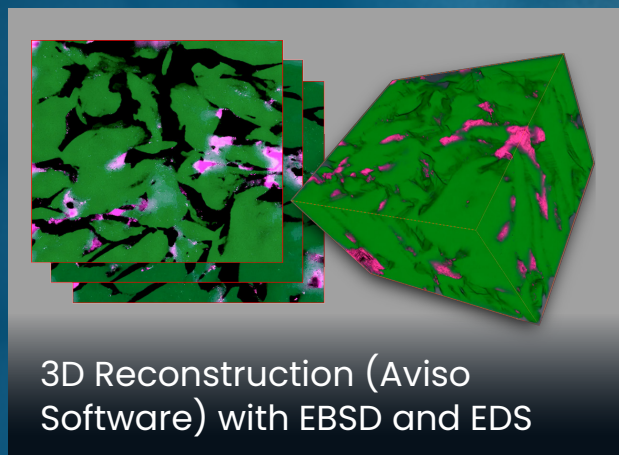
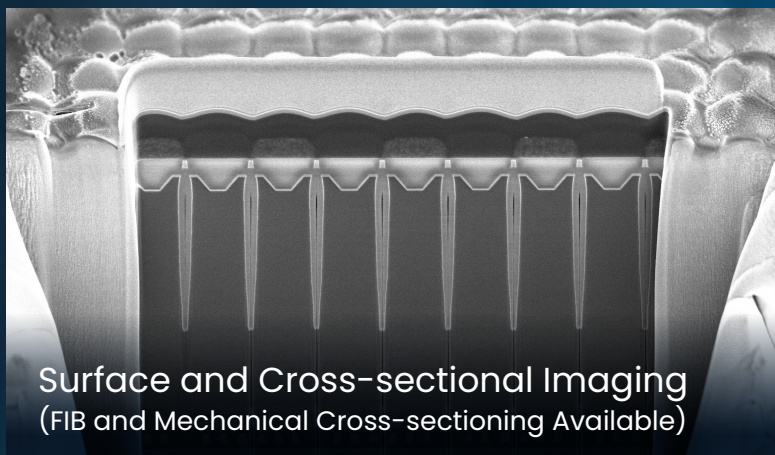


Scanning Electron Microscopy with Focused Ion Beam Services With the Covalent Platform

Deepen your microanalytical work with ultra-high-resolution imaging provided at fast and reliable turnaround times. Covalent relies on top-of-line DualBeam electron microscopy instruments that enable advanced data processing, artifact removal, and presentation-ready reporting features. Correlate structural and topographic information with spectroscopic data for element mapping in 2D scans and 3D reconstructions of your sample. The Scanning Electron Microscopy group makes partnership efficient and easy so you can probe these deeper insights with powerful analytical tools and world-class expertise.

The Solutions We Offer



Cutting-Edge Instruments



2 Thermo Scientific Helios 5 DualBeam FIB-SEM Instruments

- Helios 5 UX and Helios 5 UC
- Ultra-high resolution imaging with sub-nanometer limits
- Multiple electron and ion beam detectors
- Oxford EDS detector
- Highest quality multi-modal subsurface 3D information



Thermo Scientific Scios DualBeam FIB-SEM

- Comparable ultra-high resolution to Helios
- Images can be generated at pressures above vacuum
- Charge neutralization enables imaging of magnetic samples

Covalent's SEM and FIB Analysis Group

Covalent's world-class electron microscopy experts rely on top-of-line instrumentation and an advanced suite of imaging analysis tools to generate ultra-high-resolution images and powerful insights. With DualBeam electron microscopy, you can access combined chemical and morphological information backed by quantitative composition and dimensional measurement tools. Covalent experts will partner with you to accelerate your analysis so you can be more effective in optimizing and troubleshooting your advanced materials, parts, and devices.

Get a quote at covalentmetrology.com